

# LCR816

## Standard 16A SCRs

$I_{T(AV)}$	16 A
$V_{DRM}/V_{RRM}$	800 V
$I_{GT}$	15 mA
$T_J$	-40°C to +125°C

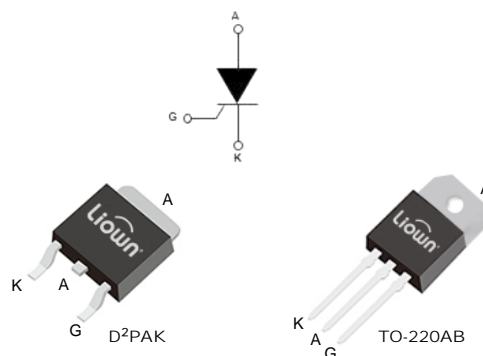
### Features

- On-state rms current,  $I_{T(RMS)}$  24A
- Repetitive peak off-state voltage,  $V_{DRM}/V_{RRM}$  800V
- Triggering gate current,  $I_{GT}$  15 mA
- Insulated package TO-220AB ins
  - Insulating voltage 2500 V rms

### Description

These standard 16A SCRs are suitable for general purpose applications.

Using clip assembly technology, they provide a superior performance in surge current capabilities.



### Absolute ratings (limiting values)

Symbol	Parameter			Value	Unit
$I_{T(RMS)}$	On-state rms current (180 °Conduction angle)	TO-220AB, D2PAK	$T_c = 100\text{ °C}$	24	A
		TO-220AB ins	$T_c = 83\text{ °C}$		
$I_{T(AV)}$	Average on-state current (180 °Conduction angle)		$T_c = 100\text{ °C}$	16	A
$I_{TSM}$	Non repetitive surge peak on-state current	$t_p = 8.3\text{ ms}$	$T_j = 25\text{ °C}$	240	A
		$t_p = 10\text{ ms}$		300	
$I^2t$	$I^2t$ Value for fusing	$t_p = 10\text{ ms}$	$T_j = 25\text{ °C}$	450	A <sup>2</sup> s
dI/dt	Critical rate of rise of on-state current $I_G = 2 \times I_{GT}$ , $t_r \leq 100\text{ ns}$	F = 60 Hz	$T_j = 125\text{ °C}$	50	A/ $\mu$ s
$I_{GM}$	Peak gate current	$t_p = 20\text{ }\mu$ s	$T_j = 125\text{ °C}$	4	A
$P_{G(AV)}$	Average gate power dissipation		$T_j = 125\text{ °C}$	1	W
$T_{stg}$ $T_j$	Storage junction temperature range			- 40 to + 150	°C
	Operating junction temperature range			- 40 to + 125	
$V_{RGM}$	Maximum peak reverse gate voltage			5	V

### Electrical Characteristics ( $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified)

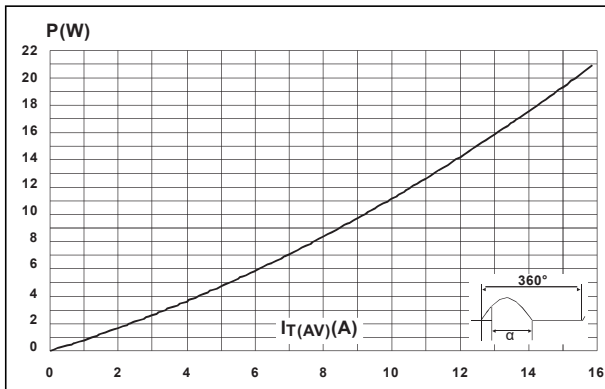
Symbol	Test conditions		Value	Unit		
$I_{GT}$	$V_D = 12\text{ V}$ $R_L = 33\ \Omega$	MIN.	4	mA		
		MAX.	15			
$V_{GT}$		MAX.	1.3	V		
$V_{GD}$	$V_D = V_{DRM}$ $R_L = 3.3\text{ k}\Omega$	$T_j = 125\text{ }^\circ\text{C}$	MIN.	0.2	V	
$I_H$	$I_T = 500\text{ mA}$ Gate open		MAX.	50	mA	
$I_L$	$I_G = 1.2 \times I_{GT}$		MAX.	90	mA	
$dV/dt$	$V_D = 67\% V_{DRM}$ Gate open	$T_j = 125\text{ }^\circ\text{C}$	MIN.	1500	V/ $\mu\text{s}$	
$V_{TM}$	$I_{TM} = 50\text{ A}$ $t_p = 380\ \mu\text{s}$	$T_j = 25\text{ }^\circ\text{C}$	MAX.	1.35	V	
$V_{t0}$	Threshold voltage		$T_j = 125\text{ }^\circ\text{C}$	MAX.	0.77	V
$R_d$	Dynamic resistance		$T_j = 125\text{ }^\circ\text{C}$	MAX.	14	m $\Omega$
$I_{DRM}$ $I_{RRM}$	$V_{DRM} = V_{RRM}$		$T_j = 25\text{ }^\circ\text{C}$	MAX.	5	$\mu\text{A}$
			$T_j = 125\text{ }^\circ\text{C}$		4	mA

### Thermal resistances

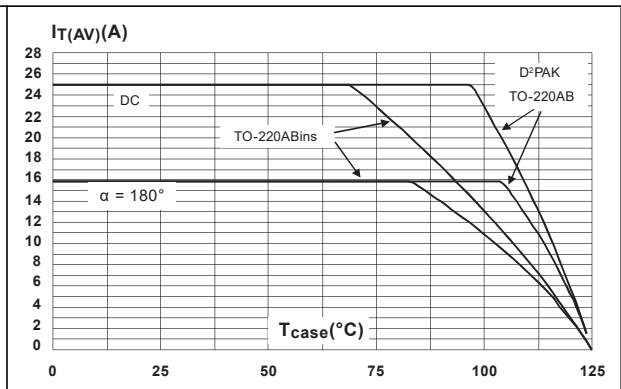
Symbol	Parameter		Value	Unit	
$R_{th(j-c)}$	Junction to case (DC)		D <sup>2</sup> PAK, TO-220AB	1.0	$^\circ\text{C/W}$
			TO-220AB ins	2.0	
$R_{th(j-a)}$	Junction to ambient (DC)	$S^{(1)} = 1\text{ cm}^2$	D <sup>2</sup> PAK	45	$^\circ\text{C/W}$
			TO-220AB, TO-220AB ins	60	

S = Copper surface under tab.

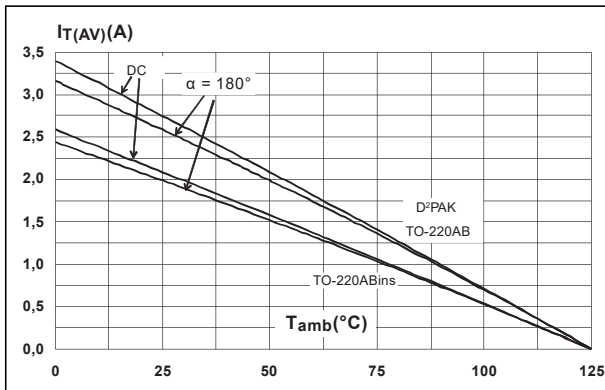
**Figure 1. Maximum average power dissipation versus average on-state current**



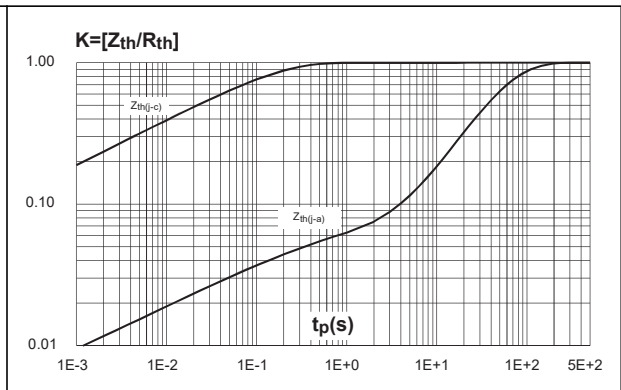
**Figure 2. Average and DC on-state current versus case temperature**



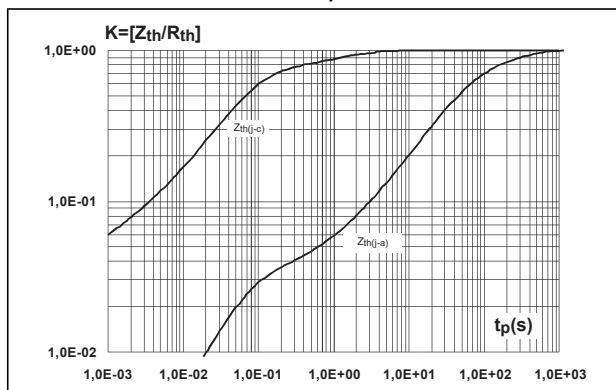
**Figure 3. Average and DC on-state current versus ambient temperature**



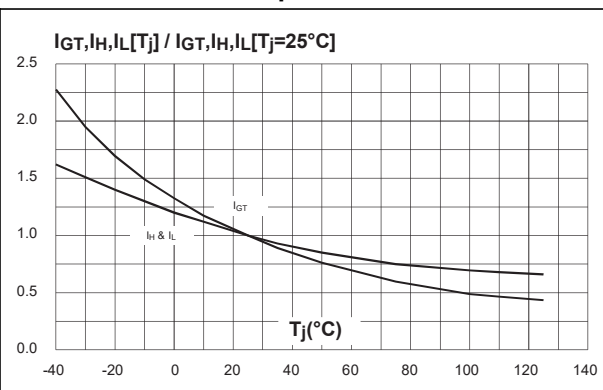
**Figure 4. Relative variation of thermal impedance versus pulse duration (D²PAK, and TO-220AB)**



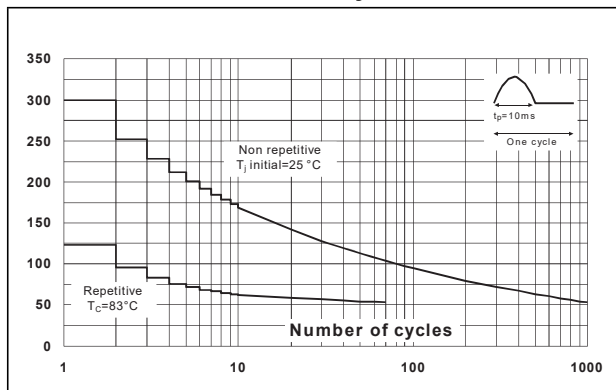
**Figure 5. Relative variation of thermal impedance versus pulse duration (TO-220AB ins)**



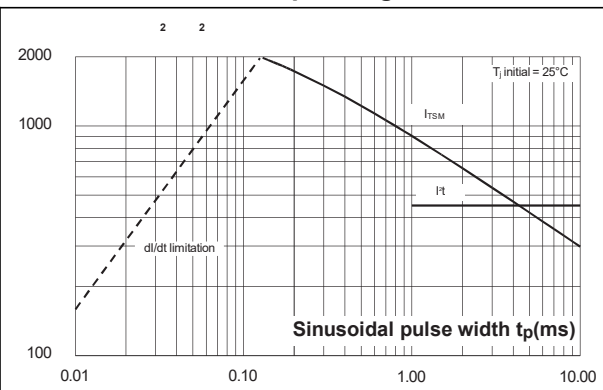
**Figure 6. Relative variation of gate trigger, holding, and latching currents versus junction temperature**



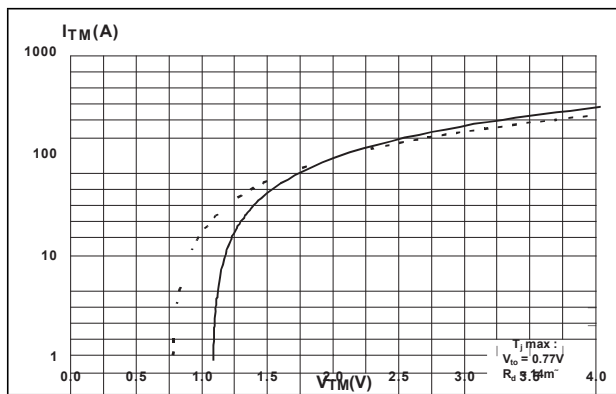
**Figure 7. Surge peak on-state current versus number of cycles**



**Figure 8. Non-repetitive surge peak on-state current, and corresponding values of I²t**



**Figure 9. On-state characteristics (maximum values)**



**Figure 10. Thermal resistance junction to ambient versus copper surface under tab (D²PAK)**

